Burn-In-Test System Serie EBI

Burn In Test System EBI/T

Test System EBI undertakes packages and terminals for a “burn in" test. It gives already in the basic equipment the unit for a parallel test of test items. The test takes place by 55 °C. This temperature will be held in the test system by ± 5°C constant. The heating phase from room temperature to “Burn In Temperature" is typical only 30 min. A controller can switch different groups of the test items and simulate different operating conditions. The test items can also run under a load. The course of these tests, i.e. groups, can be free programmed. The test chamber is provided with safety switch, which will prevent the opening of the door during the test. Only after the complete test or by stopping the test and after a certain cool down phase the chamber door can be opened.
To load the test item outputs, electronic loads or resistors can be used. Optional also the primary supply of the test item can be varied. Temperature measurement spots at the test items can be recorded and stored. It gives the possibilty to record the temperature runs at the test item. The test time can be variated from a few minutes up to a few days. With especially construced test openings the test places can be adapted to different test items. A window allows a visual control of the test items during the test. The fixed rolls permits the change of location. On the bottom of the test chamber are bars, which enable the easy transport by a fork lifter.

Burn-In-Test System Serie EBI

Burn-In-System for electronic modules

Burn-In-System for 19” rack simulation

Burn-In-System with multible chamber

Burn-In-Test System Serie EBI

Burn-In-System for parts

Burn-In-System with line back operation

Burn-In-System for motor electronic

Burn-In-Test System Serie EBI

Burn-In-System for Beamer lamp electronic

Burn-In-System in line production

Burn-In-System for EX-power supplies